ASIGURAREA CALITĂȚII – QUALITY ASSURANCE

CUPRINS – CONTENTS

In memoriam Joseph M. JURAN (1904-2008). The Quality Trilogy. A Universal Approach to Managing for Quality

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Abstract

Ten years ago, the great Quality Management Guru Joseph M. JURAN passed into eternity. In order to mark this moment, we publish one of his most representative papers, the well-known Juran Quality Trilogy. In 1987, I asked Dr. Juran to send a message addressed to the Romanian specialists in quality, together with a representative paper to be published in a Romanian technical journal. Dr. J. M. Juran send me this message together with this famous paper on "Quality Trilogy", with the permission to publish it in a Romanian journal. Dr. Juran left us with many important fundamental methods and tools during his years as the leading expert in the field of Quality Management. The Juran Quality Trilogy is made up of three important managerial tools that work together to help organizations realize the full benefits of Quality Management in the pursuit of Quality Leadership. Dr. Juran's Trilogy represents the concepts of Quality Planning, Quality Control, and Quality Improvement. In the Six Sigma language, the Quality Planning and Quality Improvement processes are called DMADV and DMAIC. Juran referred to these processes as "universal." These processes represent the sequences of events to effectively Plan, Control, and Improve Quality. These processes have been used widely in all industries around the world for many years. (ICB)

Keywords: Quality, Quality Management, Juran, Quality Trilogy, Plan, Control, Improvement

Enhancing the Quality of a Web Application through Responsive Design

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Abstract

An attractive design engages even the most fastidious users and alleviates most concerns over the investment acumen of any marketing strategy involving future web application development. Integrating responsive design ensures that the content properly displays on a large variety of terminals, including desktop computers, mobile phones and tablets. This article addresses managers, quality assurance engineers and junior developers with an interest towards qualitative web development. It highlights essential information for upcoming development and testing phases, focuses on quality and usability and virtually guarantees a successful product. Containing time-saving tips, it outlines the transformation process required to reach the stage of seamless, modern Responsive Web Design (RWD) and concentrates on the quality assurance perspective through deeper understanding of the development and testing requirements.

Keywords: Responsive design, Quality Improvement Process, Cross-platform Testing, Adaptive design

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Test, Testability and Reliability Aspects of Integrated Circuits

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Abstract

The role of testing is to detect whether something went wrong and the role of diagnosis is to determine exactly what went wrong. Testability is a design criterion and should be included in design reviews. Quiescent power supply current (IDDQ) testing of a CMOS integrated circuit is a technique for production quality and reliability improvement, design validation, and failure analysis. It has been used for many years by a few companies and has now receiving wider acceptance as an industry tool.

Keywords: ASIC, IDDQ, NNR, SEC, TCV, operational test, test methods, reliability

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Provocările migrării de la OHSAS 18001 la ISO 45001

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Abstract

This paper outlines some of the novelties brought by the new ISO 45001: 2018 standard and outlines both aspects that should be considered by organizations for their implementation and third party auditors to audit these new requirements.

Keywords: Standardization, ISO, OHSAS 18001, ISO 45001 Occupational health and safety, Communication, Implementation, Audit

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